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S1	20123	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1 or reference\$1 or standard\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:35
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S5	3041	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:46
S6	3449	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S7	126	(((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:41
S8	956	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:40

S9	40	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:56
S10	134765	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S11	3449	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:59
S12	3355	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)) and (pixel\$1 or point\$1 or feature\$1 or characteristic\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:00
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S14	125	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)) and (pixel\$1 or point\$1)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:01
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S16	1977	382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:24

S17	1411	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S18	1853	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S19	1356	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S20	749	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:30
S21	332	(((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:28
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S23	57	(((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))) and (radiation or x-ray\$1 or xray\$1 or irradiation)) and (((similarit\$4 or feature\$1) near3 (table\$1 or list\$1 or value\$1)) or scor\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S24	4	"4851678".pn.",4962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S25	5807	382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:27
S26	839	382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S27	1140	382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S28	468	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and ((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:31
S29	177	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and (((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6)) same (template\$1 or kernal\$1 or standard\$1 or pattern\$1 or mask\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:32

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S31	4	"5343390".pn.,"5962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/14 16:18
S32	8496	382/100,128,132,172,190,195,199, 200,201,202,203,204,205,217,243, 266.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:21
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S35	94	S32 and (irradiation near5 (field\$1 or area\$1 or section\$5 or segment\$4 or region\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:43
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S37	615	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:47
S38	759	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7 or comb\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:48

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1 Evaluation of a structured cesium iodide film for radiation imaging purposes

Jing, T.; Goodman, C.A.; Cho, G.; DREWERY, J.; Hong, W.S.; Lee, H.; Kaplan, Mireshghi, A.; Perez-Mendez, V.; Wildermuth, D.;
Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IE Conference Record. , 31 Oct.-6 Nov. 1993
Pages:1878 - 1882 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) **IEEE CNF**

2 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection

Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagou, M.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.; Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trim, M.; Ulrici, J.; Treis, J.;
Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 3 , June 2004
Pages:1121 - 1128

[\[Abstract\]](#) [\[PDF Full-Text \(616 KB\)\]](#) **IEEE JNL**

3 An asynchronous pixel architecture for simultaneous radiation imaging and spectroscopy on a real-time basis

Kapnistis, C.; Misiakos, K.; Haralabidis, N.; Kyriakis-Bitzaros, D.;
Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002
Pages:1802 - 1807

[\[Abstract\]](#) [\[PDF Full-Text \(244 KB\)\]](#) **IEEE JNL**

4 A novel radiation imaging sensor based on self-activated pixels

Kavadias, S.; Misiakos, K.; Loukas, D.;
Nuclear Science, IEEE Transactions on , Volume: 42 , Issue: 3 , June 1995
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5 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection

Wermes, N.; Andricek, L.; Fischer, P.; Harter, M.; Herrmann, S.; Karagounis, Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, R.; Soltau, H.; Struder, L.; Trimpl, M.; Ulrici, J.; Treis, J.;
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19- Oct. 2003
Pages:325 - 330 Vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(722 KB\)\]](#) [IEEE CNF](#)

6 Radiation imaging with 2D a-Si sensor arrays

Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;
Nuclear Science Symposium and Medical Imaging Conference, 1991., Conference Record of the 1991 IEEE , 2-9 Nov. 1991
Pages:1882 - 1886 vol.3

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7 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip

Conti, M.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;
Nuclear Science, IEEE Transactions on , Volume: 50 , Issue: 4 , Aug. 2003
Pages:869 - 877

[\[Abstract\]](#) [\[PDF Full-Text \(1541 KB\)\]](#) [IEEE JNL](#)

8 Radiation imaging with 2D a-Si sensor arrays

Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;
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Pages:1056 - 1062

[\[Abstract\]](#) [\[PDF Full-Text \(668 KB\)\]](#) [IEEE JNL](#)

9 Report from the 5th International Workshop on Radiation Imaging Detectors

Ludwig, J.;
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19- Oct. 2003
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[\[Abstract\]](#) [\[PDF Full-Text \(1118 KB\)\]](#) [IEEE CNF](#)

10 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip

Maionino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;
Nuclear Science Symposium Conference Record, 2002 IEEE , Volume: 1 , 10-

Nov. 2002
Pages:189 - 193 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(895 KB\)\]](#) [IEEE CNF](#)

11 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science Symposium and Medical Imaging Conference Record, 1995.,
IEEE , Volume: 1 , 21-28 Oct. 1995

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[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) [IEEE CNF](#)

12 Portable system for imaging of /spl alpha/, and X-ray sources with silicon pixel detectors and Medipix1 readout

Bertolucci, E.; Boerkamp, T.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russi
Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002

Pages:1845 - 1850

[\[Abstract\]](#) [\[PDF Full-Text \(573 KB\)\]](#) [IEEE JNL](#)

13 Analysis of images of radiation due to plasma-limiter interaction

Peterson, B.J.; Ashikawa, N.; Kostrioukov, A.Yu.; Nishimura, K.; Kojima, H.; S.
S.;

Plasma Science, IEEE Transactions on , Volume: 30 , Issue: 1 , Feb. 2002

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14 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;

Nuclear Science, IEEE Transactions on , Volume: 43 , Issue: 3 , June 1996

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15 Robust window discriminator for photon-counting pixel detectors

Oelmann, B.; Abdalla, M.; O'Nils, M.;

Optoelectronics, IEE Proceedings- , Volume: 149 , Issue: 2 , April 2002

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1 Optical transition radiation imaging of intense proton beams at FNA
 Scarpine, V.E.; Lumpkin, A.H.; Schappert, W.; Tassotto, G.R.;
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 Pages:1529 - 1532

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2 Terahertz radiation imaging of vortices penetrated into YBCO thin film
 Tonouchi, M.; Moto, A.; Yamashita, M.; Hangyo, M.;
 Applied Superconductivity, IEEE Transactions on , Volume: 11 , Issue: 1 , Mar 2001
 Pages:3230 - 3233

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3 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption
 Misiakos, K.; Kavadias, S.;

Nuclear Science Symposium and Medical Imaging Conference Record, 1995.,
 IEEE , Volume: 1 , 21-28 Oct. 1995
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Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagouzis, P.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.; Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trimble, M.; Ulrich, J.; Treis, J.;

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8 The feasibility of OTR imaging of high-intensity proton beams at FN/

Lumpkin, A.H.; Scarpine, V.;

Particle Accelerator Conference, 2003. PAC 2003. Proceedings of the , Volume 4 , 12-16 May 2003
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9 A high resolution ultrasonic imaging system for the detection of cervical cancer

van der Heiden, M.; Faber, G.; Ongkiehong, L.; Berkhout, A.J.;

Ultrasonics Symposium, 1996. Proceedings., 1996 IEEE , Volume: 2 , 3-6 Nov 1996
Pages:1341 - 1344 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(528 KB\)\]](#) [IEEE CNF](#)

10 Effect of multi-layers of image planes on PCB radiation

Jinsuk Kim; Kilnam Oh;

Electromagnetic Compatibility, 1996. Symposium Record. IEEE 1996 International Symposium on , 19-23 Aug. 1996
Pages:322 - 325

[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) [IEEE CNF](#)

11 Evaluation of a structured cesium iodide film for radiation imaging purposes

Jing, T.; Goodman, C.A.; Cho, G.; Drewery, J.; Hong, W.S.; Lee, H.; Kaplan, Miresghi, A.; Perez-Mendez, V.; Wildermuth, D.;

Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IE Conference Record. , 31 Oct.-6 Nov. 1993

Pages:1878 - 1882 vol.3

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Migeon, B.; Serfaty, V.; Gorkani, M.; Marche, P.;
Engineering in Medicine and Biology Magazine, IEEE, Volume: 14, Issue: 6, Dec. 1995

Pages:762 - 765

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2 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption

Misiakos, K.; Kavadias, S.;
Nuclear Science Symposium and Medical Imaging Conference Record, 1995., IEEE, Volume: 1, 21-28 Oct. 1995
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3 Development of an orthogonal-stripe CdZnTe gamma radiation imaging spectrometer

Macri, J.R.; Apotovsky, B.A.; Butler, J.F.; Cherry, M.L.; Dann, B.K.; Drake, A. Doty, F.P.; Guzik, T.G.; Larson, K.; Mayer, M.; McConnell, M.L.; Ryan, J.M.;
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Migeon, B.; Deforge, P.; Marche, P.;

Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the IEEE , Volume: 2 , 29 Oct.-1 Nov. 1998

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6 Development of an orthogonal-stripe CdZnTe gamma radiation imaging spectrometer

Macri, J.R.; Apotovsky, B.A.; Butler, J.F.; Cherry, M.L.; Dann, B.K.; Drake, A.; Doty, F.P.; Guzik, T.G.; Larson, K.; Mayer, M.; McConnell, M.L.; Ryan, J.M.; Nuclear Science Symposium and Medical Imaging Conference Record, 1995., IEEE , Volume: 1 , 21-28 Oct. 1995

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